

# Editorial

Vishwani D. Agrawal<sup>1</sup>

Received: 1 May 2017 / Accepted: 1 May 2017 / Published online: 6 May 2017  
© Springer Science+Business Media New York 2017

August 2016 was a special issue on mixed-signal test. Repeating that theme in less than a year emphasizes its significance and growing interest. Considering the expanding applications internet-of-things (IoT) is no longer a buzzword. It is clear that electronics has outgrown its optional roles and is becoming an essential part of our existence. As a result, we will be giving greater attention to the reliability and security aspects of analog and radio frequency (RF) devices.

Most special issue papers and some regular papers in *JETTA* include research previously discussed at conferences and workshops. However, they should satisfy three conditions. First, a *JETTA* paper should contain advancements over the previous version; a full paper in *JETTA* has no six-page limit. Second, the paper must pass the journal's peer review and the *JETTA* issue containing it must appear after the conference or workshop is over. Third, the *JETTA* paper should include the previous paper as a reference with an

explanation of similarities and differences between the two versions. Authors often ask whether *JETTA* requires authors to pay publication charges. The answer is that there is no page-charge.

The papers in this issue are categorized under ATE Characterization, ADC Testing, Machine Learning-Based Test, Fault Diagnosis, Device Security and Authentication, and Medical Applications.

Soon after the 21st *International Mixed-Signal Testing Workshop (IMSTW 2016)*, held in Catalunya, Spain during July 4–6, 2016, we issued a call for papers for this special issue under the guest editorship of Manuel Barragan and William Eisenstadt. All received submissions went through the journal's peer review process to select seven articles appearing here. This issue, however, contains eight articles because one other accepted direct submission to *JETTA* matched the theme. Authors of that paper are Luo, Lu, Y. Wang and L. Wang, and the responsible editor is Professor Tian Xia.

We are thankful to Professor Barragan and Professor Eisenstadt for their efforts that made this issue possible. Their Guest Editorial introduces the content.

Just when this issue gets out, *IMSTW 2017*, the 22nd workshop in the series, will be getting underway at Thessaloniki, Greece.

---

✉ Vishwani D. Agrawal  
agravwd@auburn.edu

<sup>1</sup> Department of ECE, Auburn University, 200 Broun Hall,  
Auburn, AL 36849, USA